

Dual, 10-Bit, 300Msps, Current-Output DAC with 4x/2x/1x Interpolation Filters

General Description

The MAX5858 dual, 10-bit, 300Msps digital-to-analog converter (DAC) provides superior dynamic performance in wideband communication systems. The MAX5858 integrates two 10-bit DAC cores, 2x/4x programmable digital interpolation filters, and a 1.24V reference. The MAX5858 supports single-ended and differential modes of operation. The MAX5858 dynamic performance is maintained over the entire power-supply operating range of 2.7V to 3.3V. The analog outputs support a compliance voltage of -1.0V to +1.25V.

The 4x/2x programmable interpolation filters feature excellent passband distortion and noise performance. Interpolating filters minimize the design complexity of analog reconstruction filters while lowering data bus and clock speeds of the digital interface. To reduce the I/O pin count, the DAC can also operate in interleave data mode. This allows the MAX5858 to be updated on a single 10-bit bus.

The MAX5858 features digital control of channel gain matching to within ±0.4dB in 16 0.05dB steps. Channel matching improves sideband suppression in analog quadrature modulation applications. The on-chip 1.24V bandgap reference includes a control amplifier that allows external full-scale adjustments of both channels through a single resistor. The internal reference can be disabled and an external reference may be applied for high-accuracy applications.

The MAX5858 features full-scale current outputs of 2mA to 20mA and operates from a 2.7V to 3.3V single supply. The DAC supports three modes of power-control operation: normal, low-power standby, and complete power-down. In power-down mode, the operating current is reduced to 1µA.

The MAX5858 is packaged in a 48-pin TQFP with exposed paddle (EP) for enhanced thermal dissipation and is specified for the extended (-40°C to +85°C) temperature range.

Applications

Communications SatCom, LMDS, MMDS, HFC, DSL, WLAN, Point-to-Point Microwave Links

Wireless Base Stations Direct Digital Synthesis Instrumentation/ATE

Features

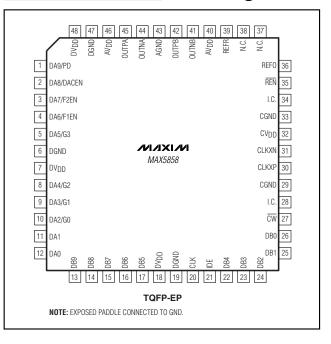
- ◆ 10-Bit Resolution, Dual DAC
- ♦ 300Msps Update Rate
- ♦ Integrated 4x/2x Interpolating Filters
- ♦ 2.7V to 3.3V Single Supply
- **♦** Full Output Swing and Dynamic Performance at 2.7V Supply
- **♦** Superior Dynamic Performance 75dBc SFDR at four = 20MHz UMTS ACLR = 63dB at four = 30.7MHz
- ♦ Programmable Channel-Gain Matching
- ♦ Integrated 1.24V Low-Noise Bandgap Reference
- ♦ Single-Resistor Gain Control
- ♦ Interleave Data Mode
- **♦ Differential Clock Input Modes**
- ♦ EV Kit Available—MAX5858 EV Kit

Ordering Information

PART	TEMP RANGE	PIN-PACKAGE
MAX5858ECM	-40°C to +85°C	48 TQFP-EP*

^{*}EP = Exposed paddle.

Pin Configuration



MIXIM

ABSOLUTE MAXIMUM RATINGS

AGND to DGND, DGND to CGND, AGND to CGND	0.3V to +0.3V
Maximum Current into Any Pin	
(excluding power supplies)	±50mA
Continuous Power Dissipation ($T_A = +70^{\circ}C$)	
48-Pin TQFP-EP (derate 36.2mW/°C above	+70°C)2.898W
Operating Temperature Range	40°C to +85°C
Storage Temperature Range	65°C to +150°C
Junction Temperature	+150°C
Lead Temperature (soldering, 10s)	+300°C

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

ELECTRICAL CHARACTERISTICS

 $(AV_{DD} = DV_{DD} = CV_{DD} = 3V, AGND = DGND = CGND = 0, f_{DAC} = 165Msps, no interpolation, external reference, V_{REF} = 1.2V, I_{FS} = 20mA, output amplitude = 0dB FS, differential output, T_A = T_{MIN} to T_{MAX}, unless otherwise noted. T_A > +25°C guaranteed by production test. T_A < +25°C guaranteed by design and characterization. Typical values are at T_A = +25°C.)$

PARAMETER	SYMBOL	CON	DITIONS	MIN	TYP	MAX	UNITS
STATIC PERFORMANCE	•			•			
Resolution				10			Bits
Integral Nonlinearity	INL	$R_L = 0$		-1.25	±0.5	+1.25	LSB
Differential Nonlinearity	DNL	Guaranteed monotor	nic, R _L = 0	-0.75	±0.25	+0.75	LSB
Offset Error	Vos			-0.5	±0.1	+0.5	LSB
Gain Error (See Gain Error	GE	Internal reference (N	ote 1)	-9	±1.5	+10	%
Parameter Definitions Section)	GL	External reference		-5	±1.5	+7	76
DYNAMIC PERFORMANCE							
Maximum Output DAC Update Rate	fDAC			300			Msps
Glitch Impulse					5		pV-s
	O SFDR	f _{DAC} = 165Msps	$f_{OUT} = 5MHz$, $T_A \ge +25^{\circ}C$	69	76		
			f _{OUT} = 20MHz		75		
Spurious-Free Dynamic Range to			f _{OUT} = 40MHz		65	dDo	alD a
Input Update Rate Nyquist			f _{OUT} = 60MHz		63		dBc
		f _{DAC} = 300Msps, 2x interpolation	$f_{OUT} = 5MHz$		76		
			$f_{OUT} = 40MHz$		78		
		2X interpolation	$f_{OUT} = 60MHz$		70		
Spurious-Free Dynamic Range	SFDR	f _{DAC} = 200Msps, 2x f _{OUT} = 40MHz, span			85		alD a
Within a Window	SEDR	f _{DAC} = 165Msps, f _{OUT} = 5MHz, span = 4MHz		78	85		dBc
Multitone Power Ratio, 8 Tones, 300kHz Spacing	MTPR	f _{DAC} = 165Msps, f _{OUT} = 20MHz			76		dBc
Adjacent Channel Leakage Ratio with UMTS	ACLR	f _{DAC} =122.88Msps, t	f _{OUT} = 30.72MHz		63		dB

ELECTRICAL CHARACTERISTICS (continued)

 $(AV_{DD}=DV_{DD}=CV_{DD}=3V,\ AGND=DGND=CGND=0,\ f_{DAC}=165Msps,\ no\ interpolation,\ external\ reference,\ V_{REF}=1.2V,\ I_{FS}=20mA,\ output\ amplitude=0dB\ FS,\ differential\ output,\ T_A=T_{MIN}\ to\ T_{MAX},\ unless\ otherwise\ noted.\ T_A>+25°C\ guaranteed\ by\ production\ test.\ T_A<+25°C\ guaranteed\ by\ design\ and\ characterization.\ Typical\ values\ are\ at\ T_A=+25°C.)$

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
Total Harmonic Distortion to Nyquist	THD	f _{DAC} = 165Msps; f _{OUT} = 5MHz		-72		dB
Noise Spectral Density	N _D	f _{DAC} = 165Msps; f _{OUT} = 5MHz		-143		dBm/Hz
Output Channel-to-Channel Isolation		fout = 5MHz		80		dB
Gain Mismatch Between Channels		f _{OUT} = 5MHz		±0.05		dB
Phase Mismatch Between Channels		f _{OUT} = 5MHz		±0.15		Degrees
Wideband Output Noise				50		pA/√Hz
ANALOG OUTPUT	•	•	•			•
Full-Scale Output Current Range	IFS		2		20	mA
Output Voltage Compliance Range			-1.00		+1.25	V
Output Leakage Current		Power-down or standby mode	-5		+5	μΑ
REFERENCE			•			
Reference Output Voltage	V _{REF0}	REN = AGND	1.14	1.24	1.32	V
Output-Voltage Temperature Drift	TCV _{REF}			±50		ppm/°C
Reference Output Drive Capability				50		μΑ
Reference Input Voltage Range		$\overline{REN} = AV_{DD}$	0.10		1.25	V
Reference Supply Rejection				0.2		mV/V
Current Gain	I _{FS} /I _{REF}			32		mA/mA
INTERPOLATION FILTER (2x inte	rpolation)		•			
		-0.005dB		0.398		
D. I. IMCHI	fout/	-0.01dB		0.402		MHz/
Passband Width	0.5f _{DAC}	-0.1dB		0.419		MHz
		-3dB		0.478		
		0.604f _{DAC} / 2 to 1.396f _{DAC} / 2		74		
Stanhand Dejection		0.600f _{DAC} / 2 to 1.400f _{DAC} / 2		62		40
Stopband Rejection		0.594f _{DAC} / 2 to 1.406f _{DAC} / 2		53		dB
		0.532f _{DAC} / 2 to 1.468f _{DAC} / 2		14		
Group Delay				18		Data clock cycles
Impulse Response Duration				22		Data clock cycles



ELECTRICAL CHARACTERISTICS (continued)

 $(AV_{DD}=DV_{DD}=CV_{DD}=3V,\ AGND=DGND=CGND=0,\ f_{DAC}=165Msps,\ no\ interpolation,\ external\ reference,\ V_{REF}=1.2V,\ I_{FS}=20mA,\ output\ amplitude=0dB\ FS,\ differential\ output,\ T_A=T_{MIN}\ to\ T_{MAX},\ unless\ otherwise\ noted.\ T_A>+25°C\ guaranteed\ by\ production\ test.\ T_A<+25°C\ guaranteed\ by\ design\ and\ characterization.\ Typical\ values\ are\ at\ T_A=+25°C.)$

PARAMETER	SYMBOL	CONDITIONS	MIN TYP	MAX	UNITS
INTERPOLATION FILTER (4x in:		0.00000000			
,		-0.005dB	0.200		
	fout/	-0.01dB	0.201		MHz/
Passband Width	0.5f _{DAC}	-0.1dB	0.210		MHz
		-3dB	0.239		
		0.302f _{DAC} / 2 to 1.698f _{DAC} / 2	74		
Ota ala ana di Daia atia a		0.300f _{DAC} / 2 to 1.700f _{DAC} / 2	63		-ID
Stopband Rejection		0.297f _{DAC} / 2 to 1.703 f _{DAC} / 2	53		dB
		0.266f _{DAC} / 2 to 1.734f _{DAC} / 2	14		
					Data
Group Delay			22		clock
					cycles Data
Impulse Response Duration			27		clock
					cycles
LOGIC INPUTS (IDE, $\overline{\text{CW}}$, $\overline{\text{REN}}$,	DA9-DA0, DB	39–DB0)			
Digital Input-Voltage High	VIH		2		V
Digital Input-Voltage Low	VIL			0.8	V
Digital Input-Current High	lΗ	$V_{IH} = 2V$	-1	+1	μΑ
Digital Input-Current Low	Ιμ_	$V_{IL} = 0.8V$	-1	+1	μΑ
Digital Input Capacitance	CIN		3		рF
DIGITAL OUTPUTS (CLK)					
Digital Output-Voltage High	VoH	ISOURCE = 0.5mA, Figure 1	0.9 × DV _{DD}		V
Digital Output-Voltage Low	V _{OL}	I _{SINK} = 0.5mA, Figure 1		$0.1 \times DV_{DD}$	٧
DIFFERENTIAL CLOCK INPUT	(CLKXP, CLK)	KN)			
Clock Input Internal Bias			CV _{DD} /2	2	V
Differential Clock Input Swing			0.5		V _{P-P}
Clock Input Impedance		Single-ended clock drive	5		kΩ
TIMING CHARACTERISTICS					
Input Data Rate		No interpolation		165	
	fdata	2x interpolation		150	Msps
		4x interpolation		75	
Output Settling Time	ts	To ±0.1% error band (Note 2)	11		ns
Output Rise Time		10% to 90% (Note 2)	2.5		ns
Output Fall Time		90% to 10% (Note 2)	2.5		ns
	-		•		•

ELECTRICAL CHARACTERISTICS (continued)

 $(AV_{DD}=DV_{DD}=CV_{DD}=3V,\ AGND=DGND=CGND=0,\ f_{DAC}=165Msps,\ no\ interpolation,\ external\ reference,\ V_{REF}=1.2V,\ I_{FS}=20mA,\ output\ amplitude=0dB\ FS,\ differential\ output,\ T_A=T_{MIN}\ to\ T_{MAX},\ unless\ otherwise\ noted.\ T_A>+25°C\ guaranteed\ by\ production\ test.\ T_A<+25°C\ guaranteed\ by\ design\ and\ characterization.\ Typical\ values\ are\ at\ T_A=+25°C.)$

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
DATA-to-CLK Rise Setup Time	tDCSR	(Note 3)	1.5			ns
DATA-to-CLK Rise Hold Time	tDCHR	(Note 3)	0.4			ns
DATA-to-CLK Fall Setup Time	tDCSF	(Note 3)	1.7			ns
DATA-to-CLK Fall Hold Time	tDCHF	(Note 3)	1.1			ns
Control Word to CW Fall Setup Time	tcws		2.5			ns
Control Word to CW Fall Hold Time	tcwH		2.5			ns
CW High Time			5			ns
CW Low Time			5			ns
DACEN Rise-to-V _{OUT} Stable	tstb			0.7		μs
PD Fall-to-V _{OUT} Stable	tPDSTB	External reference		0.5		ms
Clock Frequency at CLKXP/CLKXN Input	fDAC	Differential clock			300	MHz
CLKXP/CLKXN Differential Clock Input to CLK Output Delay	tCXD			4.6		ns
Minimum CLKXP/CLKXN Clock High Time	tcxH			1.5		ns
Minimum CLKXP/CLKXN Clock Low Time	tCXL			1.5		ns
POWER REQUIREMENTS			•			
Analog Power-Supply Voltage	AV_{DD}		2.7		3.3	V
Analog Supply Current	IAVDD	(Note 4)		45	49	mA
Digital Power-Supply Voltage	DV _{DD}		2.7		3.3	V

ELECTRICAL CHARACTERISTICS (continued)

 $(AV_{DD}=DV_{DD}=CV_{DD}=3V,\ AGND=DGND=CGND=0,\ f_{DAC}=165Msps,\ no\ interpolation,\ external\ reference,\ V_{REF}=1.2V,\ I_{FS}=20mA,\ output\ amplitude=0dB\ FS,\ differential\ output,\ T_A=T_{MIN}\ to\ T_{MAX},\ unless\ otherwise\ noted.\ T_A>+25°C\ guaranteed\ by\ production\ test.\ T_A<+25°C\ guaranteed\ by\ design\ and\ characterization.\ Typical\ values\ are\ at\ T_A=+25°C.)$

PARAMETER	SYMBOL	CON	DITIONS	MIN	TYP	MAX	UNITS	
			No interpolation		34			
		f _{DAC} = 60Msps	2x interpolation		75			
			4x interpolation		72			
District Course to Course to (Nists 4)			No interpolation		54	61	^	
Digital Supply Current (Note 4)	IDVDD	f _{DAC} = 165Msps	2x interpolation		146		mA	
			4x interpolation		140			
		f 000Mana	2x interpolation		172	186		
		f _{DAC} = 200Msps	4x interpolation		165	178		
Clock Power-Supply Voltage	CV _{DD}			2.7		3.3	V	
	ICVDD	f _{DAC} = 60Msps		25				
Clask Cupply Current (Note 4)		f _{DAC} = 165Msps		69	80	mA		
Clock Supply Current (Note 4)		f _{DAC} = 200Msps, 2x interpolation		80	94			
Standby Current	ISTANDBY	(Note 5)			4.4	4.8	mA	
Power-Down Current	I _{PD}	(Note 5)			1		μΑ	
			No interpolation		312			
		f _{DAC} = 60Msps	2x interpolation		435		1	
			4x interpolation		426		1	
Total Power Dissipation	D		No interpolation		504	570	\A/	
	Ртот	f _{DAC} = 165Msps	2x interpolation		780		mW	
			4x interpolation		762			
		face 200Mana	2x interpolation		891			
		f _{DAC} = 200Msps	4x interpolation		870			

Note 1: Including the internal reference voltage tolerance.

Note 2: Measured single ended with 50Ω load and complementary output connected to ground.

Note 3: Guaranteed by design, not production tested.

Note 4: $f_{OUT} = 5MHz$.

Note 5: All digital inputs at 0 or DV_{DD}. Clock signal disabled.

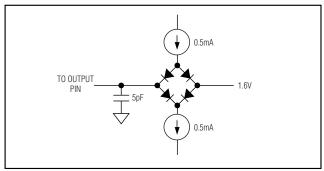
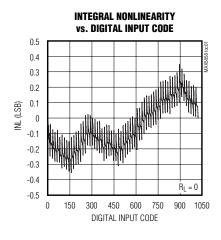
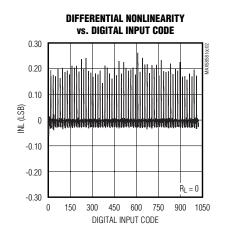


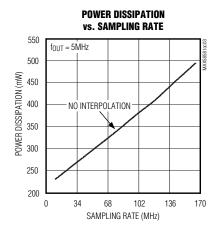
Figure 1. Load Test Circuit for CLK Outputs

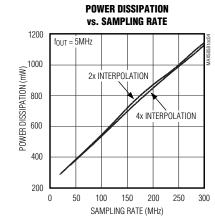
Typical Operating Characteristics

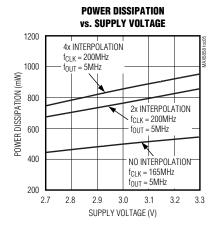
 $(AV_{DD} = DV_{DD} = CV_{DD} = 3V \pm 10\%$, AGND = DGND = CGND = 0, external reference = 1.2V, no interpolation, I_{FS} = 20mA, differential output, T_A = +25°C, unless otherwise noted.)

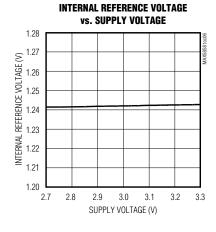


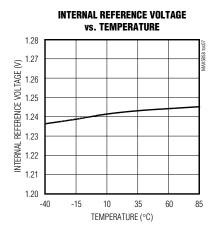


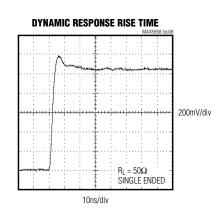


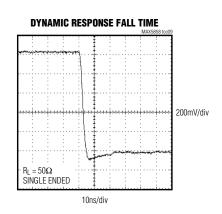






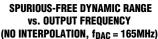


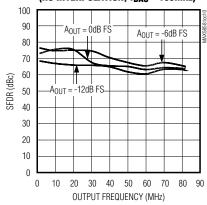




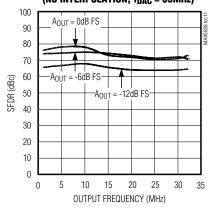
Typical Operating Characteristics (continued)

 $(AV_{DD} = DV_{DD} = CV_{DD} = 3V \pm 10\%$, AGND = DGND = CGND = 0, external reference = 1.2V, no interpolation, I_{FS} = 20mA, differential output, T_A = +25°C, unless otherwise noted.)

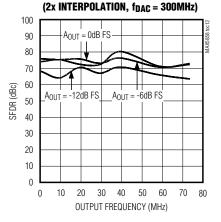




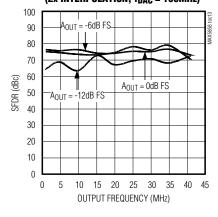
SPURIOUS-FREE DYNAMIC RANGE vs. OUTPUT FREQUENCY (NO INTERPOLATION, fdac = 65MHz)



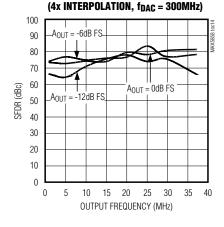
SPURIOUS-FREE DYNAMIC RANGE
vs. OUTPUT FREQUENCY



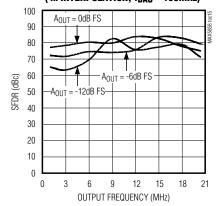
SPURIOUS-FREE DYNAMIC RANGE vs. OUTPUT FREQUENCY (2x Interpolation, fdac = 165MHz)



SPURIOUS-FREE DYNAMIC RANGE vs. OUTPUT FREQUENCY



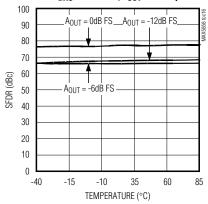
SPURIOUS-FREE DYNAMIC RANGE vs. OUTPUT FREQUENCY (4x INTERPOLATION, fDAG = 165MHz)



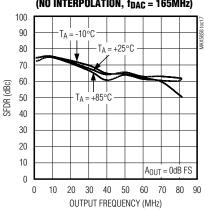
Typical Operating Characteristics (continued)

 $(AV_{DD} = DV_{DD} = CV_{DD} = 3V \pm 10\%$, AGND = DGND = CGND = 0, external reference = 1.2V, no interpolation, I_{FS} = 20mA, differential output, T_A = +25°C, unless otherwise noted.)

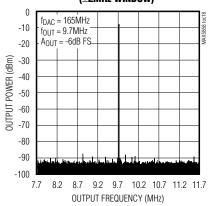
SPURIOUS-FREE DYNAMIC RANGE vs. TEMPERATURE (NO INTERPOLATION, $f_{DAC} = 165 \text{MHz}$, $f_{OUT} = 5 \text{MHz}$)



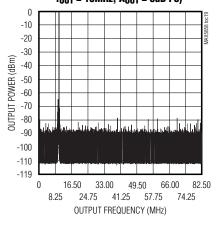
SPURIOUS-FREE DYNAMIC RANGE vs. Output Frequency (NO Interpolation, fdac = 165MHz)



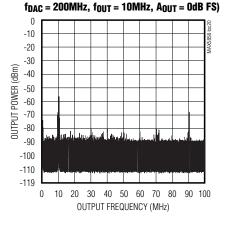
FFT PLOT (±2MHz WINDOW)



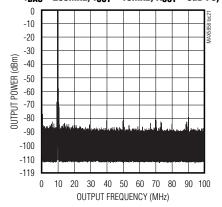
FFT PLOT FOR NYQUIST WINDOW (NO INTERPOLATION, $f_{DAC} = 165$ MHz, $f_{OUT} = 10$ MHz, $A_{OUT} = 0$ db FS)



FFT PLOT FOR DAC UPDATE NYQUIST
WINDOW (100MHz) (2x INTERPOLATION,

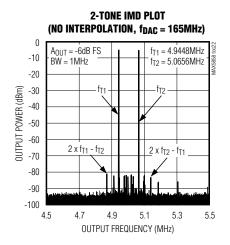


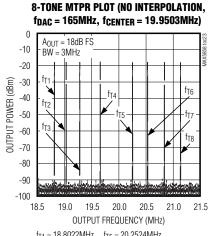
FFT PLOT FOR DAC UPDATE NYQUIST WINDOW (100MHz) (4x INTERPOLATION, fdac = 200MHz, fout = 10MHz, Aout = 0dB FS)



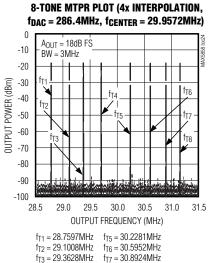
Typical Operating Characteristics (continued)

(AVDD = DVDD = CVDD = 3V ±10%, AGND = DGND = CGND = 0, external reference = 1.2V, no interpolation, IFS = 20mA, differential output, $T_A = +25$ °C, unless otherwise noted.)



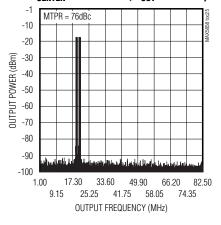


 $f_{T1} = 18.8022MHz$ $f_{T5} = 20.2524MHz$ $f_{T2} = 19.0237MHz$ $f_{T6} = 20.5344MHz$ $f_{T3} = 19.2654MHz$ $f_{T7} = 20.8365MHz$ $f_{T4} = 19.6481MHz$ $f_{T8} = 21.1386MHz$

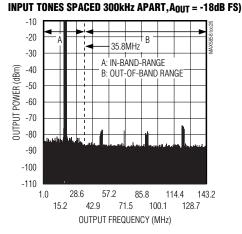


f_{T3} = 29.3628MHz $f_{T7} = 30.8924MHz$ $f_{T4} = 29.6862MHz$ $f_{T8} = 31.1546MHz$

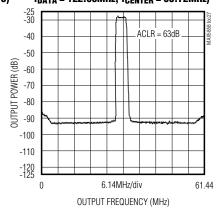
8-TONE MTPR PLOT FOR NYOUIST WINDOW (NO INTERPOLATION, $f_{DAC} = 165MHz$, fcenter = 19.9569MHz, A_{OUT} = -18dB FS)



8-TONE MTPR PLOT FOR DAC UPDATE (WITHIN A NYOUIST WINDOW) (x4 INTERPOLATION, fDAC = 286.4MHz, fCENTER = 20MHz,

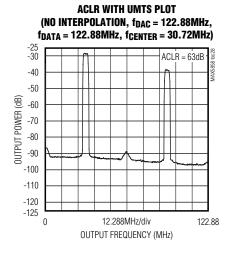


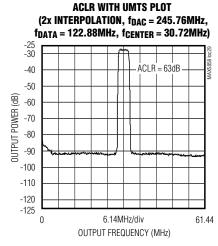
ACLR UMTS PLOT (NO INTERPOLATION, fDAC = 122.88MHz, fDATA = 122.88MHz, fcenter = 30.72MHz)

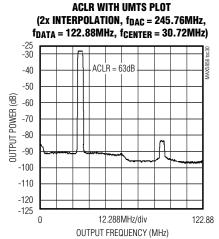


Typical Operating Characteristics (continued)

 $(AV_{DD} = DV_{DD} = CV_{DD} = 3V \pm 10\%$, AGND = DGND = CGND = 0, external reference = 1.2V, no interpolation, I_{FS} = 20mA, differential output, T_A = +25°C, unless otherwise noted.)







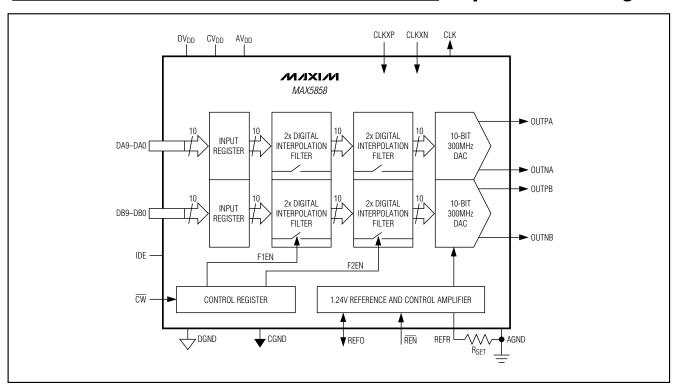
Pin Description

PIN	NAME	FUNCTION
1	DA9/PD	Channel A Input Data Bit 9 (MSB)/Power-Down Control Bit: 0: Enter DAC standby mode (DACEN = 0) or power up DAC (DACEN = 1). 1: Enter power-down mode.
2	DA8/DACEN	Channel A Input Data Bit 8/DAC Enable Control Bit: 0: Enter DAC standby mode with PD = 0. 1: Power up DAC with PD = 0. X: Enter power-down mode with PD = 1 (X = don't care).
3	DA7/F2EN	Channel A Input Data Bit 7/Second Interpolation Filter Enable Bit: 0: Interpolation mode is determined by F1EN. Enable 4x interpolation mode. (F1EN must equal 1.)
4	DA6/F1EN	Channel A Input Data Bit 6/First Interpolation Filter Enable Bit: 0: Interpolation disable. 1: Enable 2x interpolation.
5	DA5/G3	Channel A Input Data Bit 5/Channel A Gain Adjustment Bit 3
6, 19, 47	DGND	Digital Ground
7, 18, 48	DV _{DD}	Digital Power Supply. See the <i>Power Supplies, Bypassing, Decoupling, and Layout</i> section.
8	DA4/G2	Channel A Input Data Bit 4/Channel A Gain Adjustment Bit 2
9	DA3/G1	Channel A Input Data Bit 3/Channel A Gain Adjustment Bit 1

Pin Description (continued)

PIN	NAME	FUNCTION
10	DA2/G0	Channel A Input Data Bit 2/Channel A Gain Adjustment Bit 0
11	DA1	Channel A Input Data Bit 1
12	DA0	Channel A Input Data Bit 0 (LSB)
13	DB9	Channel B Input Data Bit 9 (MSB)
14	DB8	Channel B Input Data Bit 8
15	DB7	Channel B Input Data Bit 7
16	DB6	Channel B Input Data Bit 6
17	DB5	Channel B Input Data Bit 5
20	CLK	Clock Output
21	IDE	Interleave Data Mode Enable. When IDE is high, data for both DAC channels is written through port A (bits DA9–DA0). When IDE is low, channel A data is latched on the rising edge of CLK and channel B is latched on the falling edge of CLK.
22	DB4	Channel B Input Data Bit 4
23	DB3	Channel B Input Data Bit 3
24	DB2	Channel B Input Data Bit 2
25	DB1	Channel B Input Data Bit 1
26	DB0	Channel B Input Data Bit 0 (LSB)
27	CW	Active-Low Control Word Write Pulse. The control word is latched on the falling edge of $\overline{\text{CW}}$.
28, 34	I.C.	Internally Connected. Do not connect.
29, 33	CGND	Clock Ground
30	CLKXP	Differential Clock Input Positive Terminal. Bypass CLKXP with a 0.01µF capacitor to CGND when CLKXN is in single-ended mode.
31	CLKXN	Differential Clock Input Negative Terminal. Bypass CLKXN with a 0.01µF capacitor to CGND when CLKXP is in single-ended mode.
32	CV _{DD}	Clock Power Supply. See the <i>Power Supplies</i> , <i>Bypassing</i> , <i>Decoupling</i> , <i>and Layout</i> section.
35	REN	Active-Low Reference Enable. Connect REN to AGND to activate the on-chip 1.24V reference.
36	REFO	Reference I/O. REFO serves as the reference input when the internal reference is disabled. If the internal 1.24V reference is enabled, REFO serves as the output for the internal reference. When the internal reference is enabled, bypass REFO to AGND with a 0.1µF capacitor.
37, 38	N.C.	No Connection. Not internally connected.
39	REFR	Full-Scale Current Adjustment. To set the output full-scale current, connect an external resistor RSET between REFR and AGND. The output full-scale current is equal to 32 × V _{REFO} /R _{SET} .
40, 46	AV _{DD}	Analog Power Supply. See Power Supplies, Bypassing, Decoupling, and Layout section.
41	OUTNB	Channel B Negative Analog Current Output
42	OUTPB	Channel B Positive Analog Current Output
43	AGND	Analog Ground
44	OUTNA	Channel A Negative Analog Current Output
45	OUTPA	Channel A Positive Analog Current Output
_	EP	Exposed Pad. Connect to the ground plane.

Simplified Block Diagram



Detailed Description

The MAX5858 dual, high-speed, 10-bit, current-output DAC provides superior performance in communication systems requiring low-distortion analog-signal reconstruction. The MAX5858 combines two DACs with 2x/4x programmable digital interpolation filters, divide-by-N clock output, and an on-chip 1.24V reference. The current outputs of the DACs can be configured for differential or single-ended operation. The full-scale output current range is adjustable from 2mA to 20mA to optimize power dissipation and gain control.

The MAX5858 accepts an input data rate to 165MHz or a DAC conversion rate of 300MHz. The inputs are latched on the rising edge of the clock whereas the output latches on the following rising edge.

The two-stage digital interpolation filters are programmable to 4x, 2x, or no interpolation. When operating in 4x interpolation mode, the interpolator increases the DAC conversion by a factor of four, providing a fourfold increase in separation between the reconstructed waveform spectrum and its first image.

The MAX5858 features three modes of operation: normal, standby, and power-down. These modes allow efficient power management. In power-down, the MAX5858 consumes only $1\mu A$ of supply current. Wake-up time from standby mode to normal DAC operation is $0.7\mu s$.

Programming the DAC

An 8-bit control word routed through channel A's data port programs the gain matching, interpolator configuration, and operational mode of the MAX5858. The control word is latched on the falling edge of $\overline{\text{CW}}$. Table 1 represents the control word format and function.

The gain on channel A can be adjusted to achieve gain matching between two channels in a user's system. The gain on channel A can be adjusted from -0.4dB to 0.35dB in steps of 0.05dB by using bits G3 to G0 (see Table 3).

Device Power-Up and States of Operation

At power-up, the MAX5858's default configuration is no-interpolation mode with a gain of 0dB and a fully operational converter. In shutdown, the MAX5858 consumes only 1µA of supply current, and in standby the current consumption is 4.4mA. Wake-up time from standby mode to normal operation is 0.7µs.

Interpolation Filters

The MAX5858 features a two stage, 2x digital interpolating filter based on 43-tap and 23-tap FIR topology. F1EN and F2EN enable the interpolation filters. F1EN high enables the first filter for 2x interpolation and F2EN high enables the second filter for combined 4x interpolation. To bypass and disable both interpolation filters (no-interpolation mode or 1x mode) set F1EN = F2EN = 0. When set for 1x mode the filters are powered down and consume virtually no current. An illegal condition is defined by: F1EN = 0, F2EN = 1 (see Table 2 for configuration modes).

The programmable interpolation filters multiply the MAX5858 input data rate by a factor of 2x or 4x to separate the reconstructed waveform spectrum and the first image. The original spectral images, appearing around multiples of the DAC input data rate, are attenuated at least 60dB by the internal digital filters. This feature provides three benefits:

- Image separation reduces complexity of analog reconstruction filters.
- Lower input data rates eliminate board level highspeed data transmission.
- Sin(x)/x roll-off is reduced over the effective bandwidth.

Figure 2 shows an application circuit and Figure 3 illustrates a practical example of the benefits when using the MAX5858 in 4x-interpolation mode. The example illustrates signal synthesis of a 20MHz IF with a ±10MHz bandwidth. The designer can consider three options to address the design challenge. The tradeoffs for each solution are depicted in Table 4.

Table 1. Control Word Format and Function

MSB									LSB
PD	DACEN	F2EN	F1EN	G3	G2	G1	G0	Χ	X

CONTROL WORD	FUNCTION
PD	Power-Down. The part enters power-down mode if PD = 1.
DACEN	DAC Enable. When DACEN = 0 and PD = 0, the part enters standby mode.
F2EN	Filter Enable. When F2EN = 1 and F1EN = 1, 4x interpolation is enabled. When F2EN = 0, the interpolation mode is determined by F1EN.
F1EN	Filter Enable. When F1EN = 1 and F2EN = 0, 2x interpolation is active. With F1EN = 0 and F2EN = 0, the interpolation is disabled.
G3	Bit 3 (MSB) of Gain Adjust Word.
G2	Bit 2 of Gain Adjust Word.
G1	Bit 1 of Gain Adjust Word.
G0	Bit 0 (LSB) of Gain Adjust Word.

Table 2. Configuration Modes

MODE	PD	DACEN	F2EN	F1EN
No interpolation	0	1	0	0
2x interpolation	0	1	0	1
4x interpolation	0	1	1	1
Standby	0	0	Χ	Χ
Power-down	1	Χ	Χ	Χ
Power-up	0	1	Χ	Χ

X = Don't care.

F1EN = 0, F2EN = 1 illegal.

Table 3. Gain Difference Setting

GAIN ADJUSTMENT ON CHANNEL A (dB)	G3	G2	G1	G0
+0.4	0	0	0	0
0	1	0	0	0
-0.35	1	1	1	1

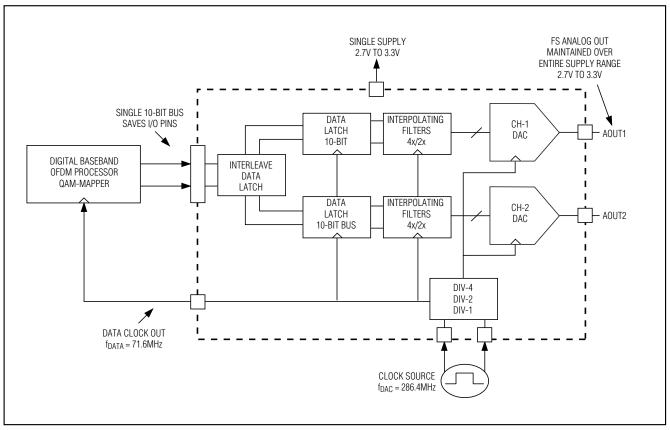


Figure 2. Typical Application Circuit

Table 4. Benefits of Interpolation

OPTION	SOLUTION	ADVANTAGE	DISADVANTAGE
1	 No interpolation 2.6x oversample fDAC = fDATA = 78MHz 	Low data rateLow clock rate	High order filter Filter gain/phase match
2	 No interpolation 8x oversample fDAC = fDATA = 240MHz Push image to fIMAGE = 210MHz 	Lower order filterFilter gain/phase match	High clock rate High data rate
3	 4x interpolation f_{DAC} = 286.4MHz, f_{DATA} = 71.6MHz Passband attenuation = 0.1dB Push image to 256MHz 	Low data rateLow order filter60dB image attenuateFilter gain/phase match	• None

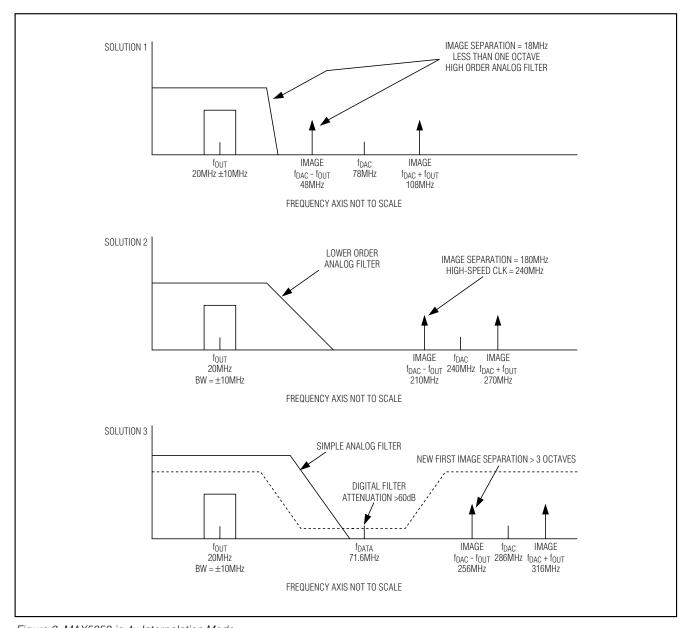


Figure 3. MAX5858 in 4x Interpolation Mode

This example demonstrates that 4x interpolation with digital filtering yields significant benefits in reducing system complexity, improving dynamic performance and lowering cost. Data can be written to the MAX5858 at much lower speeds while achieving image attenuation greater than 60dB and image separation beyond three octaves. The main benefit is in analog reconstruc-

tion filter design. Reducing the filter order eases gain/phase matching while lowering filter cost and saving board space. Because the data rate is lowered to 71.6MHz, the setup and hold times are manageable and the clock signal source is simplified, which results in improved system reliability and lower cost.

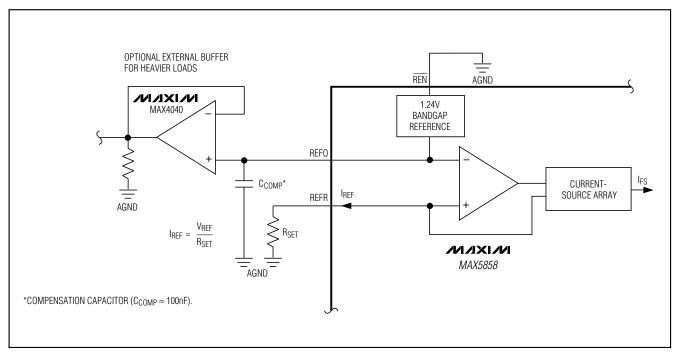


Figure 4. Setting IFS with the Internal 1.24V Reference and the Control Amplifier

Clocking Modes

Apply an external clock to CLKXP and CLKXN at the desired DAC update rate and allowable input amplitude. CLK is an output and provides the signal necessary to synchronize the input data. CLKXP and CLKXN accept a frequency range of 0 to 300MHz (see Table 5). Maintain a low capacitive load at the CLK output (not higher than 10pF for fCLK of 165MHz).

Internal Reference and Control Amplifier

The MAX5858 provides an integrated 50ppm/°C, 1.24V, low-noise bandgap reference that can be disabled and overridden with an external reference voltage. REFO serves either as an external reference input or an integrated reference output. If REN is connected to AGND, the internal reference is selected and REFO provides a 1.24V (50µA) output. Buffer REFO with an external amplifier, when driving a heavy load.

The MAX5858 also employs a control amplifier designed to simultaneously regulate the full-scale output current (IFS) for both outputs of the devices. Calculate the output current as:

$$IFS = 32 \times IREF$$

where IREF is the reference output current (IREF = VREFO/RSET) and IFS is the full-scale output current.

R_{SET} is the reference resistor that determines the amplifier output current of the MAX5858 (Figure 4). This current is mirrored into the current-source array where I_{FS} is equally distributed between matched current segments and summed to valid output current readings for the DACs.

External Reference

To disable the internal reference of the MAX5858, connect REN to AVDD. Apply a temperature-stable, external reference to drive the REFO to set the full-scale output (Figure 5). For improved accuracy and drift performance, choose a fixed output voltage reference such as the 1.24V, 25ppm/°C MAX6520 bandgap reference.

Detailed Timing

The MAX5858 accepts an input data rate up to 165MHz or the DAC conversion rate of 300MHz. The input latches on the rising edge of the clock, whereas the output latches on the following rising edge.

Figure 6 depicts the write cycle of the DACs in 4x interpolation mode. In this timing diagram, signals applied to CLKXP and CLKXN are divided by four to create the DAC's CLK signal. The MAX5858 DAC output is updated at the rate of the clock applied to CLKXP/CLKXN.

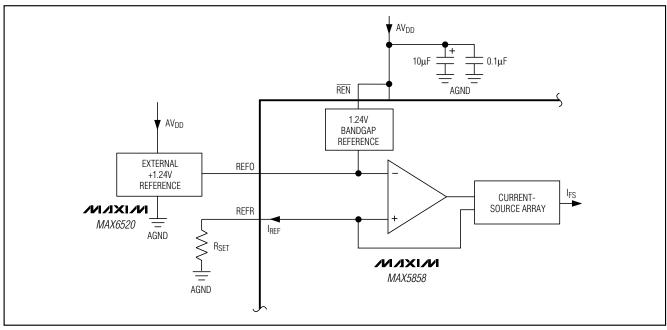


Figure 5. MAX5858 with External Reference

Table 5. Clocking Modes

F2EN	F1EN	DIFFERENTIAL CLOCK FREQUENCY (f _{CLKDIFF}) (MHz)	CLK OUTPUT (MHz)	DAC RATE (fdac)	INTERPOLATION	MAX SIGNAL BANDWIDTH (MHz)
0	0	0 to 165	FCLKDIFF	fCLKDIFF	1x	82
0	1	0 to 300	F _{CLKDIFF} /2	fCLKDIFF	2x	63
1	1	0 to 300	fCLKDIFF/4	fCLKDIFF	4x	31
1	0			Illegal		

The MAX5858 can also operate in an interleave data mode. Pulling IDE high activates this mode. In interleave mode, data for both DAC channels is written through input port A. Channel B data is written on the falling edge of the CLK signal and then channel A data is written on the following rising edge of the CLK signal. Both DAC outputs (channel A and B) are updated simultaneously on the next following rising edge of the CLK. In interleave data mode, the maximum input data rate per channel is half of the rate in noninterleave mode. The interleave data mode is attractive in applications where lower data rates are acceptable and interfacing on a single 10-bit bus is desired (Figure 7).

Applications Information

Differential-to-Single-Ended Conversion

The MAX5858 exhibits excellent dynamic performance to synthesize a wide variety of modulation schemes, including high-order QAM modulation with OFDM.

Figure 8 shows a typical application circuit with output transformers performing the required differential-to-single-ended signal conversion. In this configuration, the MAX5858 operates in differential mode, which reduces even-order harmonics, and increases the available output power.

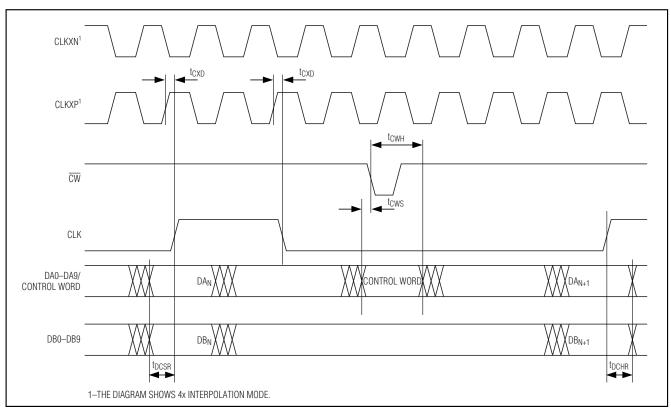


Figure 6. Timing Diagram for Noninterleave Data Mode (IDE = Low)

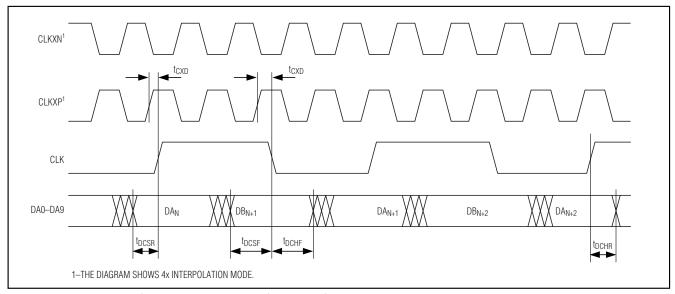


Figure 7. Timing Diagram for Interleave Data Mode (IDE = High)

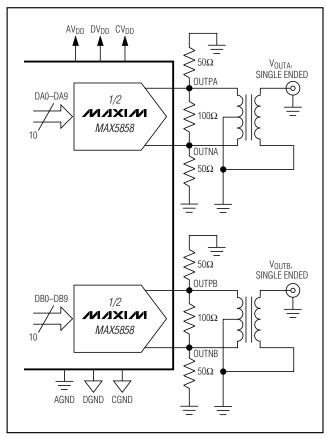


Figure 8. Application with Output Transformer Performing Differential to Single-Ended Conversion

Differential DC-Coupled Configuration

Figure 9 shows the MAX5858 output operating in differential, DC-coupled mode. This configuration can be used in communication systems employing analog quadrature upconverters and requiring a baseband sampling, dual-channel, high-speed DAC for I/Q synthesis. In these applications, information bandwidth can extend from 10MHz down to several hundred kilohertz. DC-coupling is desirable in order to eliminate long discharge time constants that are problematic with large, expensive coupling capacitors. Analog quadrature upconverters have a DC common-mode input requirement of typically 0.7V to 1.0V. The MAX5858 differential I/Q outputs can maintain the desired full-scale frequency spectrum at the required 0.7V to 1.0V DC commonmode level when powered from a single 2.85V (±5%) supply. The MAX5858 meets this low-power requirement with minimal reduction in dynamic range while eliminating the need for level-shifting resistor networks.

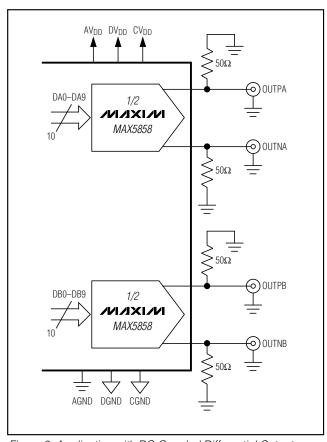


Figure 9. Application with DC-Coupled Differential Outputs

Power Supplies, Bypassing, Decoupling, and Layout

Grounding and power-supply decoupling strongly influence the MAX5858 performance. Unwanted digital crosstalk can couple through the input, reference, power-supply, and ground connections, which can affect dynamic specifications, like signal-to-noise ratio or spurious-free dynamic range. In addition, electromagnetic interference (EMI) can either couple into or be generated by the MAX5858. Observe the grounding and power-supply decoupling guidelines for high-speed, high-frequency applications. Follow the power supply and filter configuration to realize optimum dynamic performance.

Use of a multilayer printed circuit (PC) board with separate ground and power-supply planes is recommended. Run high-speed signals on lines directly above the ground plane. The MAX5858 has separate analog and digital ground buses (AGND, CGND, and DGND,

respectively). Provide separate analog, digital, and clock ground sections on the PC board with only one point connecting the three planes. The ground connection points should be located underneath the device and connected to the exposed paddle. Run digital signals above the digital ground plane and analog/clock signals above the analog/clock ground plane. Digital signals should be kept away from sensitive analog, clock, and reference inputs. Keep digital signal paths short and metal trace lengths matched to avoid propagation delay and data skew mismatch.

The MAX5858 includes three separate power-supply inputs: analog (AVDD), digital (DVDD), and clock (CVDD). Use a single linear regulator power source to branch out to three separate power-supply lines (AVDD, DVDD, CVDD) and returns (AGND, DGND, CGND). Filter each power-supply line to the respective return line using LC filters comprising ferrite beads and $10\mu F$ capacitors. Filter each supply input locally with $0.1\mu F$ ceramic capacitors to the respective return lines.

Note: To maintain the dynamic performance of the *Electrical Characteristics*, ensure the voltage difference between DV_{DD} , AV_{DD} , and CV_{DD} does not exceed 150mV.

Thermal Characteristics and Packaging Thermal Resistance

48-lead TQFP-EP:

$$\theta_{JA} = 37^{\circ}C/W$$

Keep the device junction temperature below +125°C to meet specified electrical performance. Lower the power-supply voltage to maintain specified performance when the DAC update rate approaches 300Msps and the ambient temperature equals +85°C.

The MAX5858 is packaged in a 48-pin TQFP-EP package, providing greater design flexibility, increased thermal efficiency, and optimized AC performance of the DAC. The EP enables the implementation of grounding techniques, which are necessary to ensure highest performance operation.

In this package, the data converter die is attached to an EP leadframe with the back of this frame exposed at the package bottom surface, facing the PC board side of the package. This allows a solid attachment of the package to the PC board with standard infrared (IR)-flow soldering techniques. A specially created land pattern on the PC board, matching the size of the EP (5mm × 5mm), ensures the proper attachment and grounding of the DAC. Designing vias* into the land area and

implementing large ground planes in the PC board design will allow for highest performance operation of the DAC. Use an array of 3 x 3 (or greater) vias (≤0.3mm diameter per via hole and 1.2mm pitch between via holes) for this 48-pin TQFP-EP package.

Dynamic Performance Parameter Definitions

Adjacent Channel Leakage Ratio (ACLR)

Commonly used in combination with wideband codedivision multiple-access (WCDMA), ACLR reflects the leakage power ratio in dB between the measured power within a channel relative to its adjacent channel. ACLR provides a quantifiable method of determining out-of-band spectral energy and its influence on an adjacent channel when a bandwidth-limited RF signal passes through a nonlinear device.

Total Harmonic Distortion (THD)

THD is the ratio of the RMS sum of all essential harmonics (within a Nyquist window) of the input signal to the fundamental itself. This can be expressed as:

THD=
$$20 \times \log \left(\sqrt{(V2^2 + V3^2 + V4^2 ... + ... VN^2)} / V1 \right)$$

where V_1 is the fundamental amplitude, and V_2 through V_N are the amplitudes of the 2nd through Nth order harmonics.

Spurious-Free Dynamic Range (SFDR)

SFDR is the ratio of RMS amplitude of the carrier frequency (maximum signal component) to the RMS value of their next-largest spectral component. SFDR is usually measured in dBc with respect to the carrier frequency amplitude or in dB FS with respect to the DAC's full-scale range. Depending on its test condition, SFDR is observed within a predefined window or to Nyquist.

Multitone Power Ratio (MTPR)

A series of equally spaced tones are applied to the DAC with one tone removed from the center of the range. MTPR is defined as the worst-case distortion (usually a 3rd-order harmonic product of the fundamental frequencies), which appears as the largest spur at the frequency of the missing tone in the sequence. This test can be performed with any number of input tones; however, four and eight tones are among the most common test conditions for CDMA- and GSM/EDGE-type applications.

^{*}Vias connect the land pattern to internal or external copper planes.

Intermodulation Distortion (IMD)

The two-tone IMD is the ratio expressed in dBc of either output tone to the worst 3rd-order (or higher) IMD products.

Static Performance Parameter Definitions

Integral Nonlinearity (INL)

Integral nonlinearity (INL) is the deviation of the values on an actual transfer function from a line drawn between the end points of the transfer function, once offset and gain errors have been nullified. For a DAC, the deviations are measured at every individual step.

Differential Nonlinearity (DNL)

Differential nonlinearity (DNL) is the difference between an actual step height and the ideal value of 1 LSB. A DNL error specification no more negative than -1 LSB guarantees monotonic transfer function.

Offset Error

Offset error is the current flowing from positive DAC output when the digital input code is set to zero. Offset error is expressed in LSBs.

Gain Error

A gain error is the difference between the ideal and the actual full-scale output current on the transfer curve, after nullifying the offset error. This error alters the slope of the transfer function and corresponds to the same percentage error in each step. The ideal current is defined by reference voltage at VREFO / IREF x 32.

Settling Time

The settling time is the amount of time required from the start of a transition until the DAC output settles to its new output value to within the converter's specified accuracy.

Glitch Impulse

A glitch is generated when a DAC switches between two codes. The largest glitch is usually generated around the midscale transition, when the input pattern transitions from 011...111 to 100...000. This occurs due to timing variations between the bits. The glitch impulse is found by integrating the voltage of the glitch at the midscale transition over time. The glitch impulse is usually specified in pV-s.

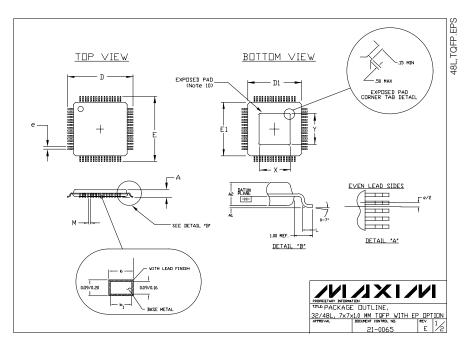
Chip Information

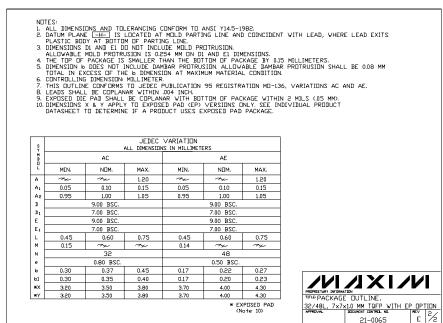
TRANSISTOR COUNT: 178,376

PROCESS: CMOS

Package Information

(The package drawing(s) in this data sheet may not reflect the most current specifications. For the latest package outline information, go to www.maxim-ic.com/packages.)





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